

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 0039-7684-2 SRD DIV		SERIAL NO. NEW DIV. APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hisako AOYAMA, et al.			
				FILING DATE HEREWITH		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>KB</i>	AA	4,091,406	MAY '78	LEWIS	257	760	—
<i>KB</i>	AB	4,789,648	DEC. '88	CHOW, ET AL.	437	225	—
<i>KB</i>	AC	5,300,813	APR. '94	JOSHI, ET AL.	257	752	—
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>KB</i>	AO	0040745	DEC. '70	JAPAN			
<i>KB</i>	AP	0040515	OCT. '72	JAPAN			
<i>KB</i>	AQ	0242331	OCT. '87	JAPAN			
<i>KB</i>	AR	0082653	MAR. '89	JAPAN			
<i>KB</i>	AS	2-78769	NOV. '90	JAPAN			
<i>KB</i>	AT	0270256	DEC. '91	JAPAN			
<i>KB</i>	AU	0343541	DEC. '93	JAPAN			
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>KB</i>	AW	IBMTDB, Lithographic Patterns With a Barrier Liner, vol. 32, No. 103, Mar. 1990, pp. 114-115					
<i>KB</i>	AX	IBMTDB, Copper Multilevel Interconnections, vol. 33, No. 11, Apr. 1991, pp. 299-300					
<i>KB</i>	AY	IBMTDB, AG Metallurgy System for Integrated Circuit Devices, vol. 13, No. 2, Jul. 1970, pp. 511-512					
	AZ						
Examiner <i>Kurt Eaton</i>					Date Considered <i>10/17/00</i>		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.